

<b>Notice of References Cited</b>	Application/Control No. 10/802,902		Applicant(s)/Patent Under Reexamination YUAN ET AL.	
	Examiner Golam M. M. Shameem, Ph.D.		Art Unit 1626	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,523,314	06-1996	Bue-Valleskey et al.	514/369
*	B	US-4,965,155	10-1990	Nishiguchi et al.	430/59.1
*	C	US-4,791,126	12-1988	Tanouchi et al.	514/369
*	D	US-4,831,045	05-1989	Tanouchi et al.	514/369
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Reiter et al (1995): STN International HCAPLUS database, Columbus (Ohio), accession number, 1995: 380326.
	V	Andreasch Rudolf (1911): STN International HCAPLUS database, Columbus (Ohio), accession number, 1911: 9676.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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